

SEMiX604GAL12E4s



SEMiX® 4s

Trench IGBT Modules

SEMiX604GAL12E4s

Features

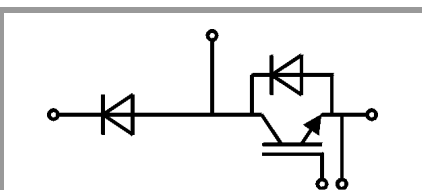
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$
- Dynamic values apply to the following combination of resistors:
 $R_{Gon,main} = 1,0 \Omega$
 $R_{Goff,main} = 6,2 \Omega$
 $R_{G,X} = 2,2 \Omega$
 $R_{E,X} = 0,5 \Omega$



GAL

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit	
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$	1200	V	
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	916	A
		$T_c = 80^\circ\text{C}$	704	A
I_{Cnom}		600	A	
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	1800	A	
V_{GES}		-20 ... 20	V	
t_{psc}	$V_{CC} = 800\text{ V}$ $V_{GE} \leq 20\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_j = 150^\circ\text{C}$	10	μs
T_j		-40 ... 175	$^\circ\text{C}$	
Inverse diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	707	A
		$T_c = 80^\circ\text{C}$	529	A
I_{Fnom}		600	A	
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$	1800	A	
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	3240	A	
T_j		-40 ... 175	$^\circ\text{C}$	
Freewheeling diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	707	A
		$T_c = 80^\circ\text{C}$	529	A
I_{Fnom}		600	A	
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$	1800	A	
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	3240	A	
T_j		-40 ... 175	$^\circ\text{C}$	
Module				
$I_{t(RMS)}$	$T_{terminal} = 80^\circ\text{C}$	600	A	
T_{stg}		-40 ... 125	$^\circ\text{C}$	
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V	

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.8	2.05	V
		$T_j = 150^\circ\text{C}$	2.2	2.4	V
V_{CE0}	chipelevel	$T_j = 25^\circ\text{C}$	0.8	0.9	V
		$T_j = 150^\circ\text{C}$	0.7	0.8	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.7	1.9	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	2.5	2.7	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 24\text{ mA}$	5	5.8	6.5	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^\circ\text{C}$		5	mA
		$T_j = 150^\circ\text{C}$			mA
C_{ies}	$V_{CE} = 25\text{ V}$		37.2		nF
C_{oes}	$V_{GE} = 0\text{ V}$		2.32		nF
C_{res}			2.04		nF
Q_G	$V_{GE} = -8\text{ V...} + 15\text{ V}$		3400		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		1.25		Ω

SEMiX604GAL12E4s



SEMiX® 4s

Trench IGBT Modules

SEMiX604GAL12E4s

Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

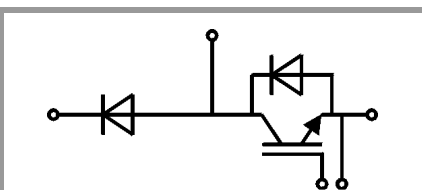
Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$
- Dynamic values apply to the following combination of resistors:
 $R_{Gon,main} = 1,0 \Omega$
 $R_{Goff,main} = 6,2 \Omega$
 $R_{G,X} = 2,2 \Omega$
 $R_{E,X} = 0,5 \Omega$

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$	$T_j = 150^\circ\text{C}$		374		ns
t_r	$I_C = 600 \text{ A}$	$T_j = 150^\circ\text{C}$		85		ns
E_{on}	$V_{GE} = \pm 15 \text{ V}$	$T_j = 150^\circ\text{C}$		35		mJ
$t_{d(off)}$	$R_{G on} = 1.7 \Omega$	$T_j = 150^\circ\text{C}$		1277		ns
t_f	$R_{G off} = 6.9 \Omega$	$T_j = 150^\circ\text{C}$		114		ns
E_{off}	$di/dt_{on} = 7100 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		110		mJ
	$di/dt_{off} = 6350 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$				
$R_{th(j-c)}$	per IGBT				0.049	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 600 \text{ A}$	$T_j = 25^\circ\text{C}$		2.1	2.46	V
	$V_{GE} = 0 \text{ V}$	$T_j = 150^\circ\text{C}$		2.1	2.4	V
	chiplevel					
V_{F0}		$T_j = 25^\circ\text{C}$	1.1	1.3	1.5	V
	chiplevel	$T_j = 150^\circ\text{C}$	0.7	0.9	1.1	V
r_F		$T_j = 25^\circ\text{C}$	1.1	1.4	1.6	m Ω
	chiplevel	$T_j = 150^\circ\text{C}$	1.7	1.9	2.1	m Ω
I_{RRM}	$I_F = 600 \text{ A}$	$T_j = 150^\circ\text{C}$		430		A
Q_{rr}	$di/dt_{off} = 6000 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		100		μC
E_{rr}	$V_{GE} = -15 \text{ V}$	$T_j = 150^\circ\text{C}$		44		mJ
	$V_{CC} = 600 \text{ V}$	$T_j = 150^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.086	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 600 \text{ A}$	$T_j = 25^\circ\text{C}$		2.1	2.46	V
	$V_{GE} = 0 \text{ V}$	$T_j = 150^\circ\text{C}$		2.1	2.4	V
	chiplevel					
V_{F0}		$T_j = 25^\circ\text{C}$	1.1	1.3	1.5	V
	chiplevel	$T_j = 150^\circ\text{C}$	0.7	0.9	1.1	V
r_F		$T_j = 25^\circ\text{C}$	1.1	1.4	1.6	m Ω
	chiplevel	$T_j = 150^\circ\text{C}$	1.7	1.9	2.1	m Ω
I_{RRM}	$I_F = 600 \text{ A}$	$T_j = 150^\circ\text{C}$		430		A
Q_{rr}	$di/dt_{off} = 6000 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		100		μC
E_{rr}	$V_{GE} = -15 \text{ V}$	$T_j = 150^\circ\text{C}$		44		mJ
	$V_{CC} = 600 \text{ V}$	$T_j = 150^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.086	K/W
Module						
L_{CE}				22		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7		m Ω
		$T_C = 125^\circ\text{C}$		1		m Ω
$R_{th(c-s)}$	per module			0.03		K/W
M_s	to heat sink (M5)		3		5	Nm
M_t		to terminals (M6)	2.5		5	Nm
						Nm
w					400	g
Temperature Sensor						
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5 \text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[\text{K}]$;			$3550 \pm 2\%$		K



GAL

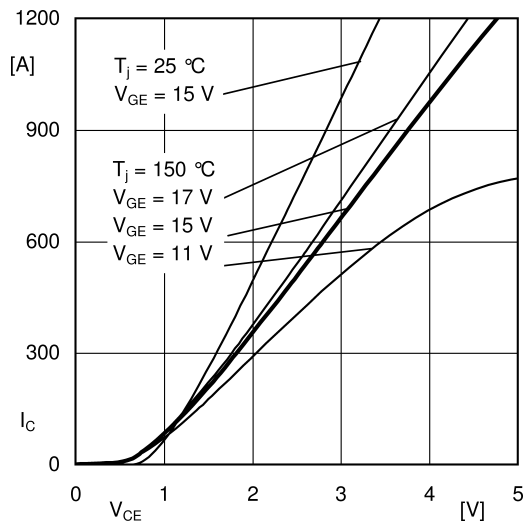


Fig. 1: Typ. output characteristic, inclusive R_{CC+EE}

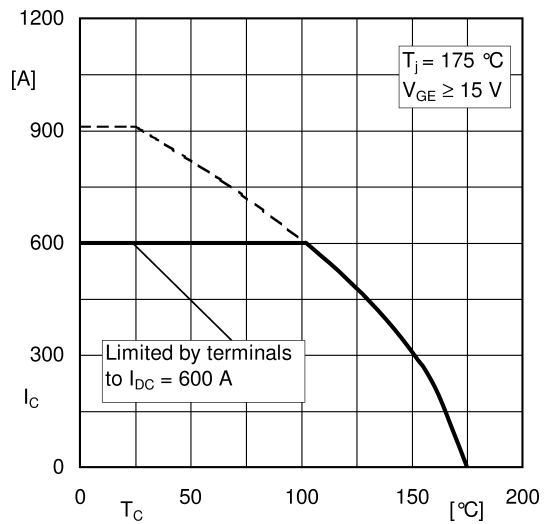


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

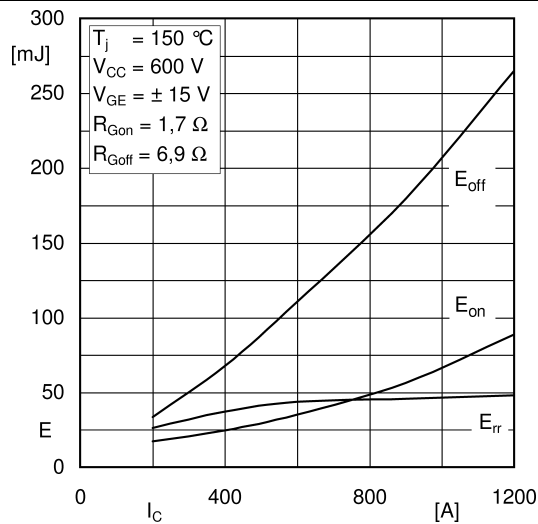


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

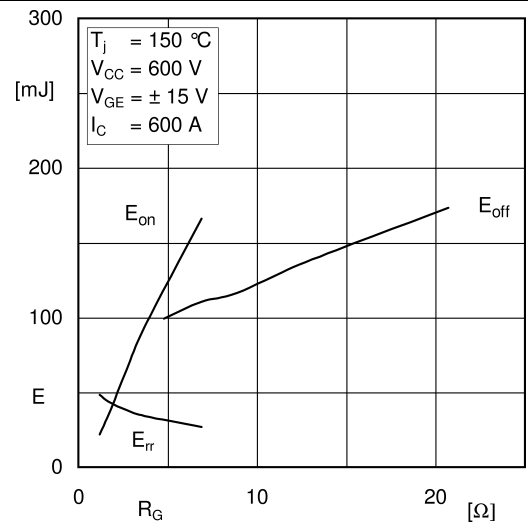


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

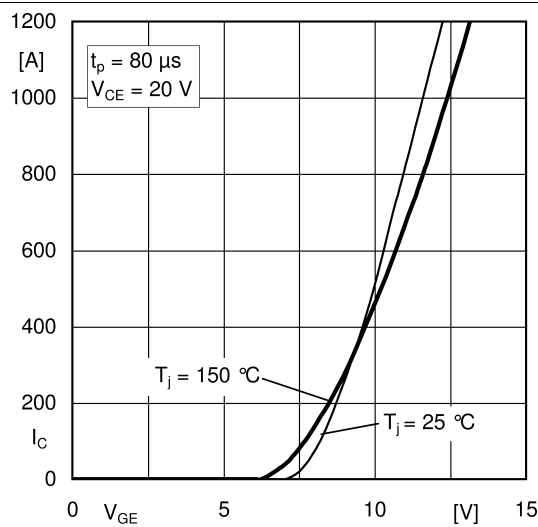


Fig. 5: Typ. transfer characteristic

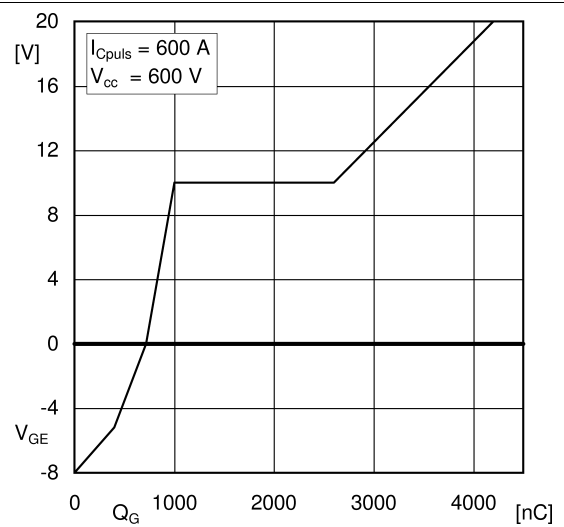


Fig. 6: Typ. gate charge characteristic

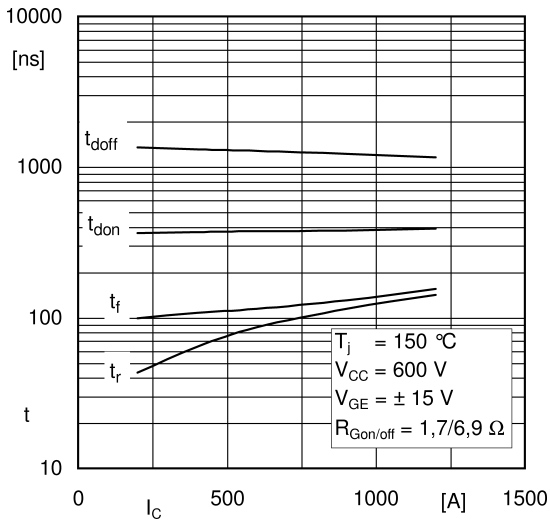


Fig. 7: Typ. switching times vs. I_C

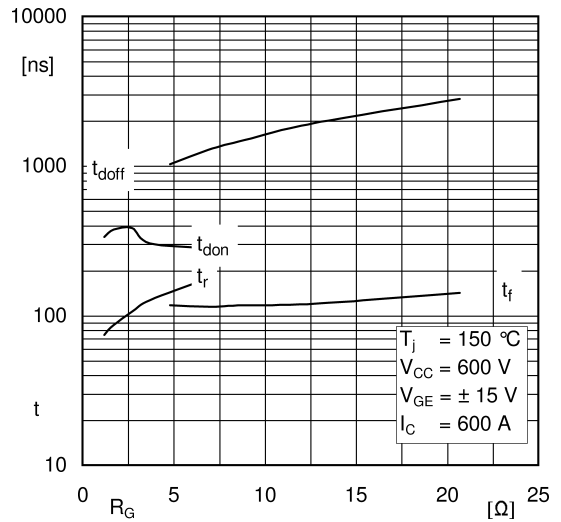


Fig. 8: Typ. switching times vs. gate resistor R_G

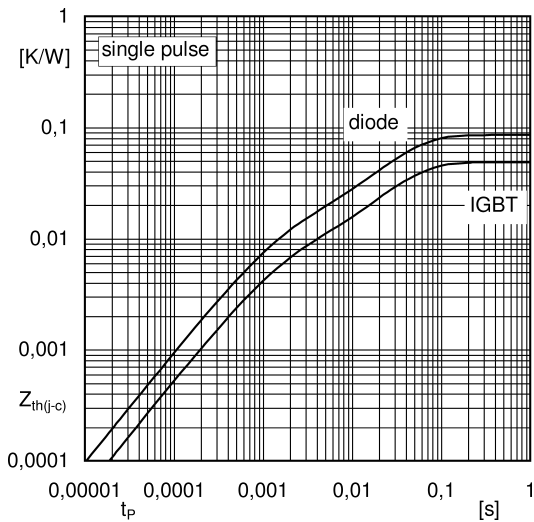


Fig. 9: Typ. transient thermal impedance

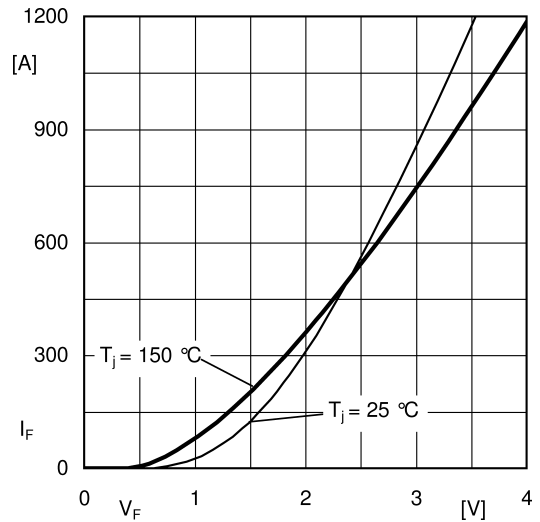


Fig. 10: Typ. CAL diode forward charact., incl. R_{CC+EE}

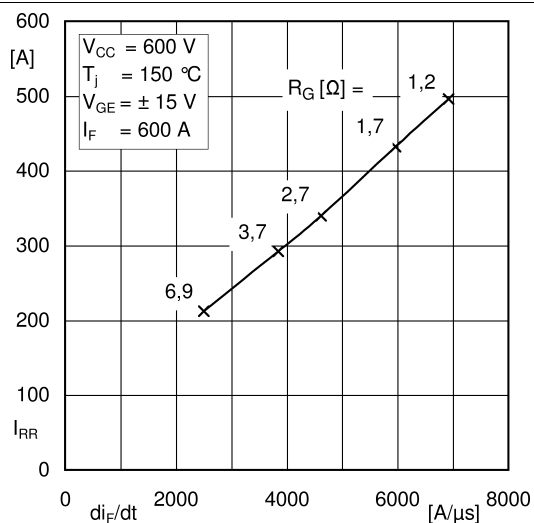


Fig. 11: Typ. CAL diode peak reverse recovery current

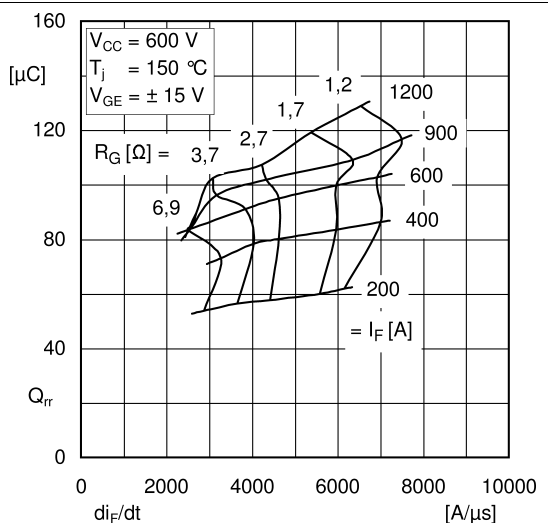
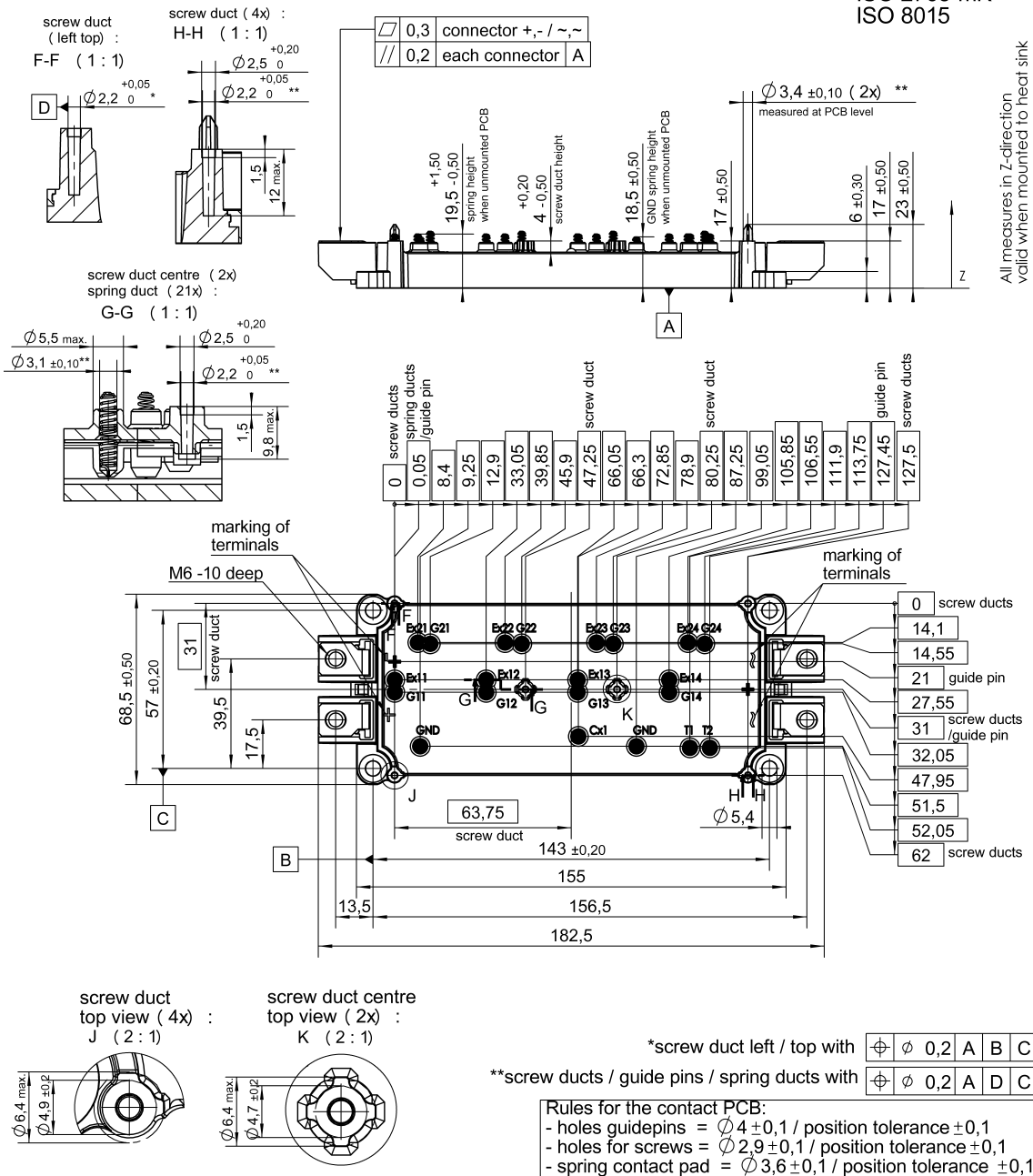


Fig. 12: Typ. CAL diode recovery charge

SEMiX604GAL12E4s

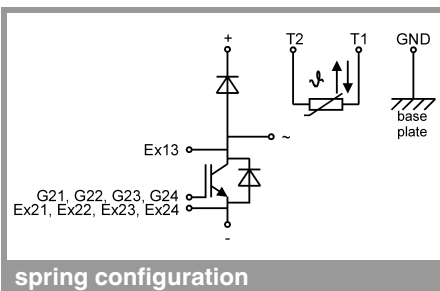
Case: SEMiX 4s

general tolerance:
ISO 2768-mK
ISO 8015



All measures in Z-direction valid when mounted to heat sink

SEMiX 4s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.